

# Spring-loaded test probe GKS-967 305 130 A 2001

Item GKS-967-0006

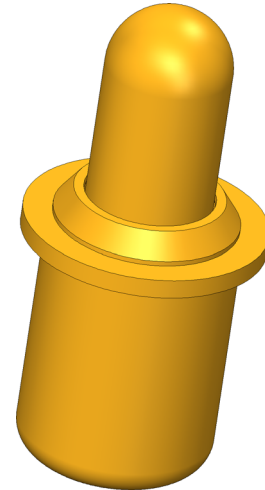


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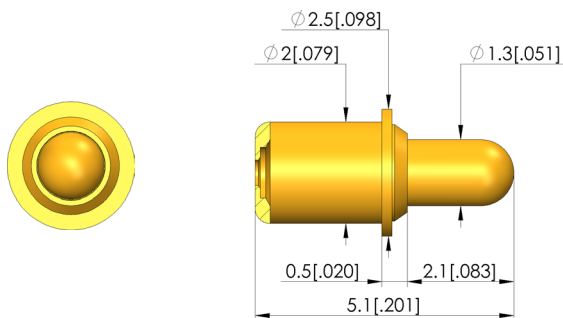
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- Short-stroke probes ensure a reliable signal and power supply, as well as a quick exchange of assemblies in case of maintenance
- For the construction of easily separable electronic interfaces, such as in charging trays for electronic devices
- Particularly suitable for use in applications where space for overall length is limited
- Compensation of possible height and component tolerances
- Stainless steel versions for temperatures from -100 °C up to +200 °C available

## INGUN SELECTION



1:1



### General data

Product group:	Assorted test probes
Sub-product group:	Short stroke GKS / charge and transfer GKS
Series:	GKS-967
Grid:	3 mm [118 mil]
Contacting from:	Pad, Female connector
Magnetic:	Yes
Installation type:	Plug-in
Quick-exchange system:	Yes
Adjustable installation height:	No
Non-rotating:	No
Compatible receptacle(s):	KS-967, KS-967 25, KS-967 50
Min. temperature:	- 40 °C [- 104 °F]
Max. temperature:	+ 80 °C [+ 176 °F]
RoHS-compliant:	RoHS-3;6c

### Electrical data

Current load capacity / rated current:	8 A
Typical resistance (Ri):	<10 mOhm

### Mechanical data

Total length:	5.1 mm [.200 in]
Barrel diameter:	2 mm [.078 in]
Maximum stroke:	1.2 mm [.047 in]
Spring pre-load:	0.57 N [2.05 ozf]
Collar height:	01
Spring force at working stroke:	2 N [7.19 ozf]
Recommended working stroke:	1 mm [.039 in]

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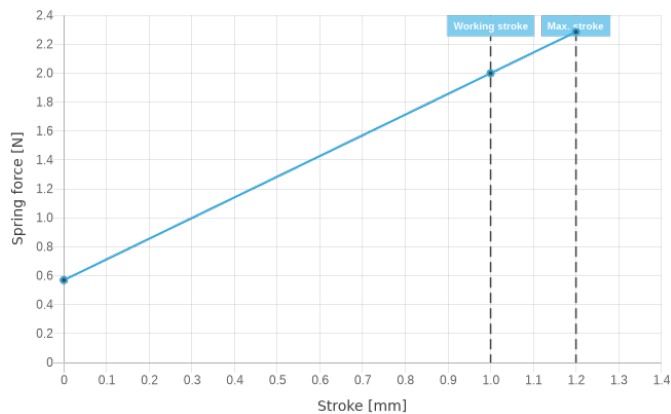


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### Tip style data

Tip style: 05 bullet-nosed (full radius)  
Tip diameter: 1.3 mm [.051 in]  
Tip style surface: A gold  
Tip style material: 3 CuBe



### INGUN Prüfmittelbau GmbH

Max-Stromeyer-Straße 162  
78467, Constance, Germany  
Phone +49 7531 8105-0  
Customer hotline +49 7531 8105-888  
Fax +49 7531 8105-65  
info@ingun.com



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